

Gaussian Process Classification Using Image Deformation

ABSTRACT

An image deformation algorithm is integrated with a Gaussian process classifier for application to remote-sensing tasks in which data is in the form of imagery. To combine these disparate techniques, we introduce a novel kernel covariance function for the Gaussian process that allows us to incorporate the result of the image deformation algorithm into a rigorous Bayesian classification framework. The resulting classifier is completely non-parametric in the sense that no parameters or hyperparameters must be learned. The promise of the proposed algorithm is demonstrated on a data set of real, measured land mine data.

Image Deformation

Gaussian Processes

Novel Covariance Function

Classification

Summary:

- A new, novel covariance function integrates the result of an image deformation algorithm into a Gaussian process classification framework
- Method is relevant when data points are initially in the form of images
- Approach obviates feature extraction process
- Image deformation algorithm permits large-scale deformations, preserves topology of structure in original image, and requires no human assistance
- Gaussian process classifier is general and has no parameters to learn
- Paper and extensive additional details available at www.duke.edu/~dpw5

- **Image deformation objective:** Deform a template image (T) into a study image (S)
- Simplified viscous fluid model governs the non-rigid deformation process
- Model explains how “particles” (image pixels) “flow” (are displaced) in the image during deformation
- Pixel displacement (u) is driven by a set of body forces (b)
- Body forces are manifested by a difference between the template and study images
- Model PDE is solved for velocity (v) of each pixel location (x, y)
- Process is conducted iteratively until deformed template image matches study image

$$\mu \nabla^2 \mathbf{v}(x, y) + (\lambda + \mu) \nabla (\nabla \cdot \mathbf{v}(x, y)) + \mathbf{b}(x, y) = \mathbf{0}$$

- Discretize spatial derivatives using second-order finite difference method
- Solve resulting matrix equation for velocity via successive overrelaxation

$$\mathbf{v}(x, y) = \frac{\partial \mathbf{u}(x, y)}{\partial t} + \left([\mathbf{v}(x, y)]^T \nabla \right) \mathbf{u}(x, y)$$

- Discretize temporal derivative using forward Euler integration
- Solve resulting equation for displacement

$$(x', y') = (x, y) - (u_x^{(t)}(x, y), u_y^{(t)}(x, y))$$

- Calculate new pixel locations

$$\mathbf{b}^{(t)}(x, y) = -\alpha (\mathbf{T}(x', y') - \mathbf{S}(x, y)) (\nabla \mathbf{T}(x', y'))$$

- Re-compute body forces

• A **Gaussian process (GP)** is a collection of random variables, any finite number of which has a joint Gaussian distribution.

• A GP is fully specified by a mean function and a (kernel) covariance function.

• Covariance function provides measure of similarity between pairs of data points.

• The problem of learning a GP classifier is the problem of learning the hyperparameters of the covariance function.

• Implementation of GP employed probit model and Expectation-Propagation approach.

• A new, **novel covariance function** integrates the result of the image deformation algorithm into the Gaussian process classification framework

$$K_{ij} = k(x_i, x_j) = \exp \left\{ -\frac{1}{2} g(x_i, x_j; \theta) \right\}$$

$$g(x_i, x_j; \theta) = \Delta(x_i, x_j) + \Delta(x_j, x_i)$$

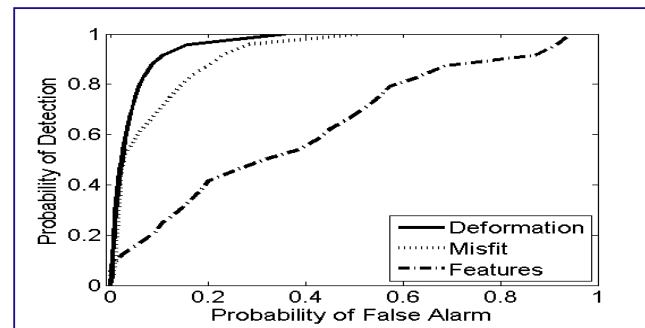
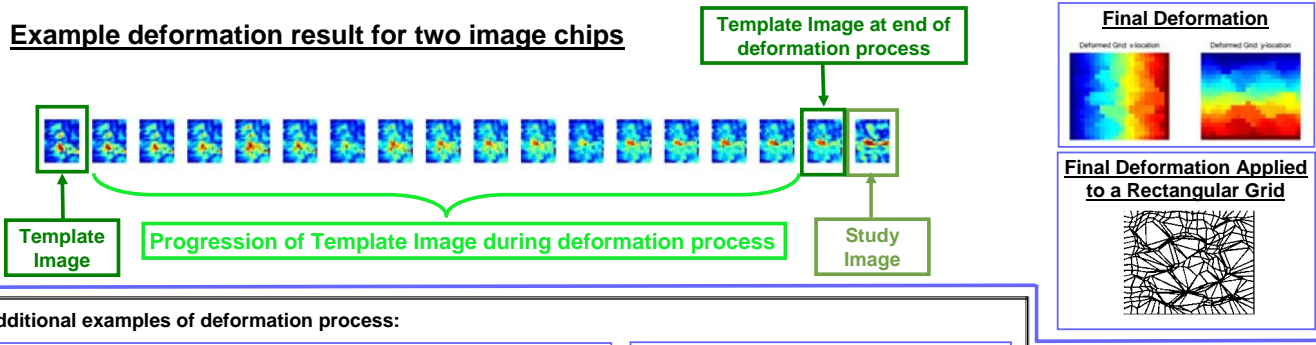
• Deformation process provides measure of similarity between pair of images

• Average distance by which each pixel in the image must be displaced to deform the i -th image into the j -th image:

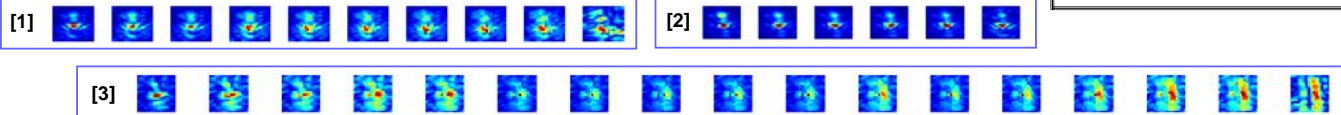
$$\Delta(x_i, x_j) = \frac{1}{N_r N_c} \sum_{r=1}^{N_r} \sum_{c=1}^{N_c} \sqrt{(u_x(r, c))^2 + (u_y(r, c))^2}$$

• No covariance function hyperparameters to learn for GP classifier

Example deformation result for two image chips



Additional examples of deformation process:



Objective: Detect land mines in a scene from an airborne sensor that collects a ground-penetrating radar image.

Misfit: New covariance function, but with misfit defined (without performing deformation) as

$$\Delta(x_i, x_j) = \sqrt{\frac{1}{N_r N_c} \sum_{r=1}^{N_r} \sum_{c=1}^{N_c} (x_i(r, c) - x_j(r, c))^2}$$

Features: Extract 3 features from each chip; use standard (Gaussian) covariance function.

110 objects (25 mines, 85 clutter) detected, each characterized by a 20 pixel by 20 pixel image chip.

Train GP classifier on 2 objects (1 mine and 1 clutter, randomly selected), test on remaining 108 objects.

ROC curves are averages over 1000 trials.